

This command runs for the time specified by the option <run-time>, and collects SMART data at the frequency specified by the option <freq>. If the output file name is not specified, this command will generate a file name that include model string and serial number of the device.

If the test-name option is specified, it will be recorded in the log file and be used as part of the log file name.

OPTIONS

-r <NUM>, --run-time=<NUM>

(optional) Number of hours to log data (default = 20 hours)

-f <NUM>, --freq=<NUM>

(optional) How often you want to log SMART data (0.25 = 15' , 0.5 = 30' , 1 = 1 hour, 2 = 2 hours, etc.). Default = 10 hours.

-o <FILE>, --output-file=<FILE>

(optional) Name of the log file (give it a name that easy for you to remember what the test is). You can leave it blank too, the file name will be generated as <model string>-<serial number>-<test name>.txt.

-n <NAME>, --test-name=<NAME>

(optional) Name of the test you are doing. We use this string as part of the name of the log file.

EXAMPLES

? Temperature characterization:

```
# nvme virtium save-smart-to-vtview-log /dev/yourDevice --run-time=100 --record-frequency=0.25
--test-name=burn-in-at-(-40)
```

? Endurance testing:

```
# nvme virtium save-smart-to-vtview-log /dev/yourDevice --run-time=100 --record-frequency=1
--test-name=Endurance-test-JEDEC-219-workload
```

? Just logging: Default logging is run for 20 hours and log every 10 hours.

```
# nvme virtium save-smart-to-vtview-log /dev/yourDevice
```

NVME

Part of the nvme-user suite